



Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10651821	MATHIEU ET AL.
	Examiner Chang, Rick K	Art Unit 3729


Notes	Date	Examiner
east search	6/19/06	RC

U.S. Patent and Trademark Office	Part of Paper No.: 20060619
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<i>Interference Searched</i> 	Application/Control No.	Applicant(s)/Patent Under Reexamination
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Class	SubClass	Date	Examiner
29,22,4398	subs. under searched	6/19/06	RC

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	<p>Examiner</p> <p>Chang, Rick K</p>	<p>Art Unit</p> <p>3729</p>

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